

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/602,848	TANAKA ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	W. Patty Chen	2871

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner